

FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S) (Use several sheets if necessary)				ATTY DOCKET NO. 03500.017975		APPLICATION NO. National. Phase of PCT/JP2004/004072 filed 3/24/04 10/549900	
				APPLICANT SHUNICHI ISHIHARA			
				FILING DATE Concurrently Herewith		GROUP N.Y.A.	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
/X.T./		5,403,771	04/04/95	Nishida et al.	437	89	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
/X.T./	JP	3-228324	10/09/91	Japan	H01L	21/208	Abstract
/X.T./	JP	2001-217442A	08/10/01	Japan	H01L	31/04	Abstract
/X.T./	JP	2001-332494A	11/30/01	Japan	H01L	21/20	Abstract
/X.T./	JP	9-312258	12/02/97	Japan	H01L	21/20	Abstract
/X.T./	JP	04-225282	08/14/92	Japan	H01L	31/04	Abstract
/X.T./	JP	10-107302	04/24/98	Japan	H01L	31/04	Abstract
/X.T./	JP	2001-237446A	08/31/01	Japan	H01L	31/04	Abstract
/X.T./	JP	5-36611	02/12/05	Japan	H01L	21/205	Abstract
/X.T./	W0	92/12542	07/23/92	EPO	H01L	31/18	Abstract
/X.T./	DE	41 93 392 T1	12/10/92	Germany	H01L	31/0392	Abstract
OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)							
/X.T./		"Investigation of Polycrystalline Silicon Deposition on Glass Substrates", Zhengrong Shi et al., Solar Energy Materials and Solar Cells 31 (1993) 51-60, Holland, pgs. 51-60					
EXAMINER				DATE CONSIDERED			
/Xiuyu Tai/				03/13/2008			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.